



Journal Name

ARTICLE

Supplementary

Design of interfaces in efficient $\text{Ln}_2\text{NiO}_{4+\delta}$ ($\text{Ln} = \text{La, Pr}$) cathode for SOFCs application

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FULLPROF refinement of the XRD patterns of the $\text{Ln}_2\text{NiO}_{4+\delta}$ ($\text{Ln} = \text{La}, \text{Pr}$) films prepared by ESD on a screen printed CGO layer on a CGO pellet.

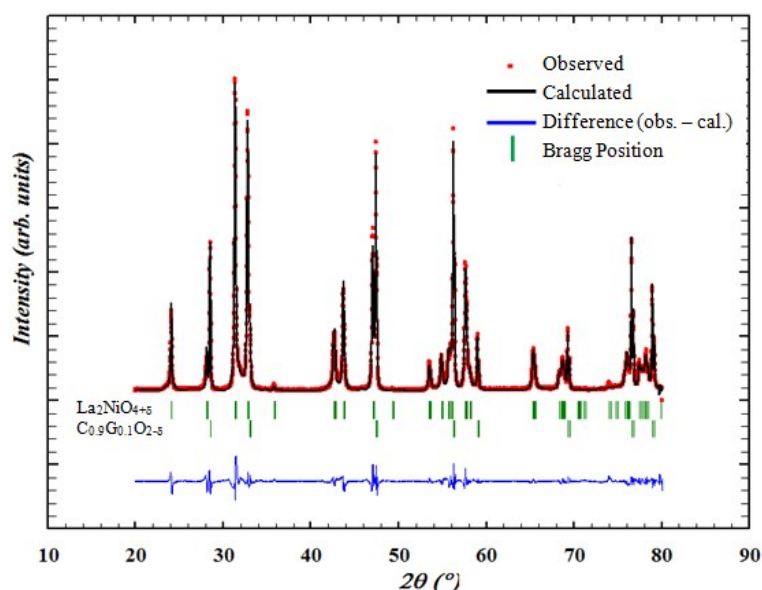


Fig. S1 FULLPROF refinement of the XRD patterns of $\text{La}_2\text{NiO}_{4+\delta}$ film deposited by ESD on a screen printed CGO layer on a CGO pellet (Fit parameters: $\chi^2 = 12.2$, Bragg R-factor = 1.272 and RF-factor = 0.637 for $\text{La}_2\text{NiO}_{4+\delta}$; Bragg R-factor = 0.925 and RF-factor = 0.442 for CGO).

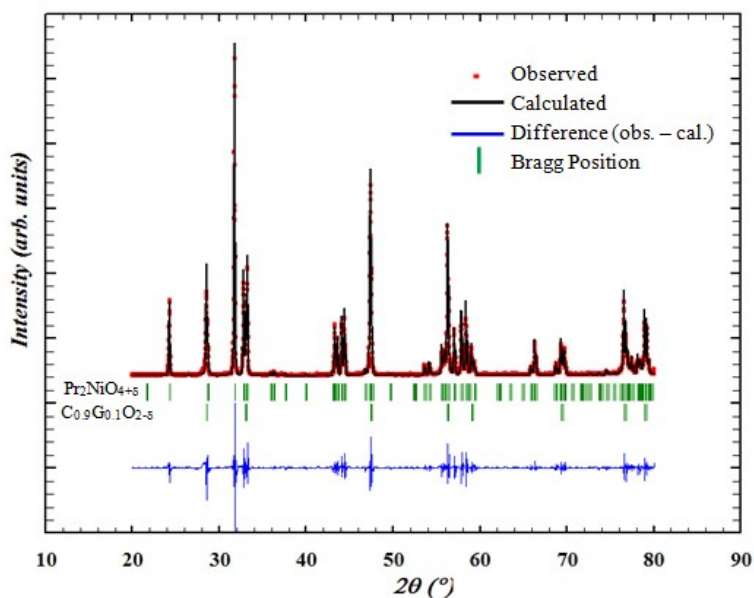


Fig. S2 FULLPROF refinement of the XRD patterns of $\text{Pr}_2\text{NiO}_{4+\delta}$ film deposited by ESD on a screen printed CGO layer on a CGO pellet (Fit parameters: $\chi^2 = 26.2$, Bragg R-factor = 1.13 and RF-factor = 0.601 for $\text{Pr}_2\text{NiO}_{4+\delta}$; Bragg R-factor = 0.556 and RF-factor = 0.319 for CGO).

Oxygen overstoichiometry by TGA:

TGA curves of $\text{La}_2\text{NiO}_{4+\delta}$ and $\text{Pr}_2\text{NiO}_{4+\delta}$ are shown in **Fig. S3**. Two weight changes are observed: the first one occurs around 350 °C, corresponding to the reduction of Ni^{3+} into Ni^{2+} (the oxygen overstoichiometry being reduced down to $\delta = 0$). The second weight loss characterizes the complete reduction of LnNO into La_2O_3 , Pr_2O_3 and Ni . The δ value has been calculated from both values of the weight changes using mole conservation principle.

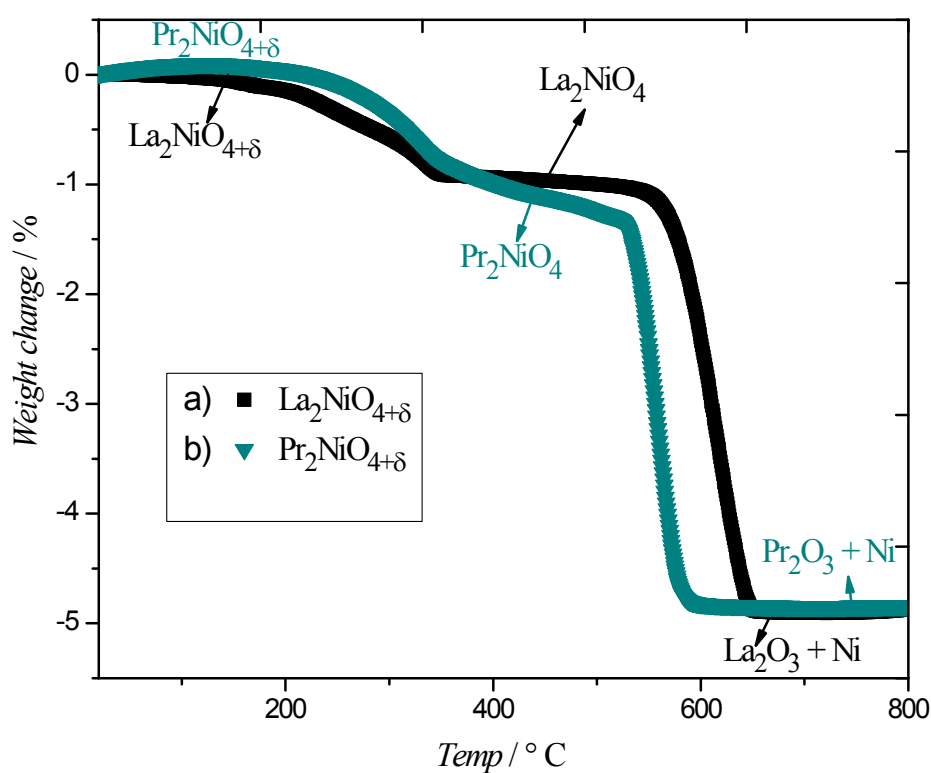


Fig. S3 TGA curves of $\text{La}_2\text{NiO}_{4+\delta}$ and $\text{Pr}_2\text{NiO}_{4+\delta}$.

Micrographs of sample 5:

Fig. S4 shows the SEM micrographs of sample 5, the LaNO cross section and the CGO-LaNO composite base-layer of the LaNO triple layer design on CGO substrate using sequentially SP and ESD.

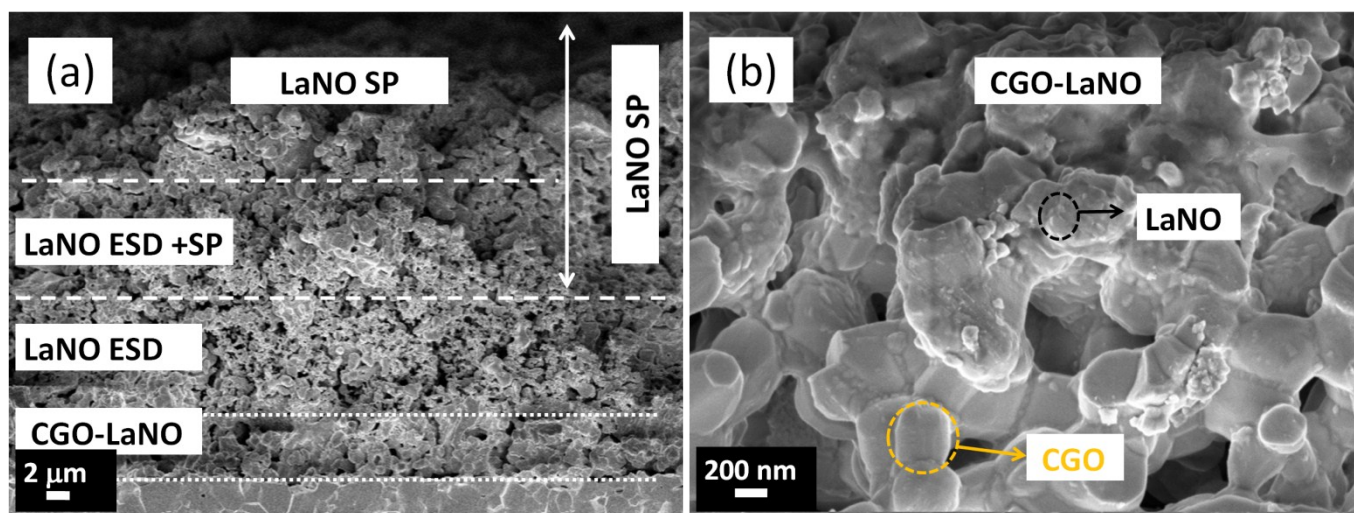


Fig. S4 SEM micrographs of sample 5: (a) cross section, (b) CGO-LaNO sub-layer on CGO electrolyte.

The experimental and fitted impedance spectra at 600 °C from the inset of **Fig. 8b**, is shown in **Fig. S5** along with capacitances and exponents of CPE for all 6 architectures in Table S1.

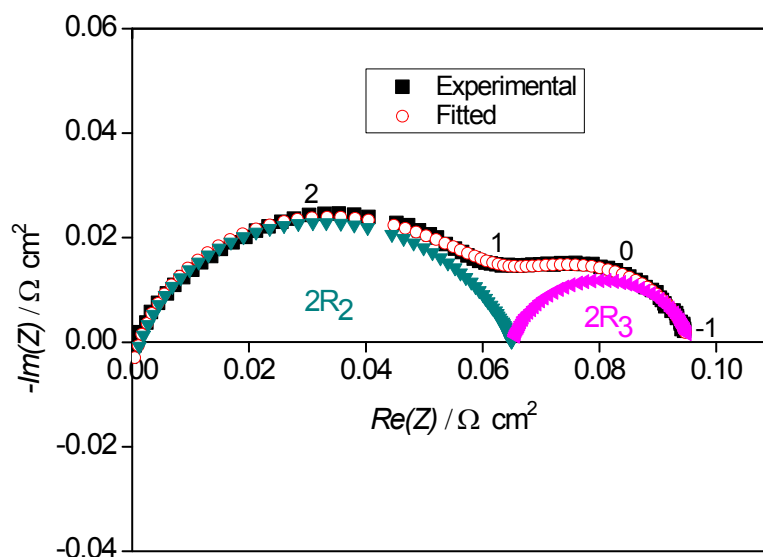


Fig. S5 Nyquist plots recorded at 600 °C in air at OCV for sample 6. The numbers indicate the logarithm of the measuring frequency.

Table S1 Capacitances ($F\text{ cm}^{-2}$) and exponents of CPE for all six architectures (estimated error is $< 5\%$).

Sample	CPE ₁			CPE ₂			CPE ₃		
	n	Q	C ₁	n	Q	C ₂	n	Q	C ₃
Sample 1	0.5552	0.0051	5.8×10^{-5}	0.8224	0.0022	3.3×10^{-3}	-----	-----	-----
Sample 2	0.8805	0.0049	9.3×10^{-4}	0.9036	0.0063	1.8×10^{-3}	-----	-----	-----
Sample 3	0.7529	0.0092	7.1×10^{-4}	0.8062	0.0074	1.2×10^{-3}	0.9719	9.23	5.6
Sample 4	-----	-----	-----	0.9435	0.0531	2.6×10^{-2}	0.8242	5.34	2.6
Sample 5	0.9055	0.0088	3.3×10^{-3}	0.8827	0.0093	3.9×10^{-3}	0.8454	5.79	2.6
Sample 6	-----	-----	-----	0.7688	0.1609	2.4×10^{-2}	0.8387	7.50	3.3